

SEU SCREENING USING AN AM-BE NEUTRON SOURCE

Matteo Cecchetto^{1,2} (matteo.cecchetto@cern.ch), **Rubén García Alía¹**, **Fabio Pozzi¹**,
Slawosz Uznanski¹, **Frédéric Wrobel²**

¹CERN (CH-1211 Geneva 23, Switzerland), ²University of Montpellier IES - UMR UM/CNRS (F-34097 Montpellier, France)



1. Abstract

Irradiation tests performed with an **Americium-Beryllium (Am-Be) neutron source at CERN**, demonstrated that this radiation environment can be used to **induce SEUs in commercial SRAM memories**. The flux assessment was performed through **FLUKA simulations** using the model of the facility. The upset events measured with the aforementioned source and those retrieved by typical **mono-energetic facilities are compared**, showing that the **Am-Be can be efficiently used for screening of components**.

2. Introduction

- The Single Event Upset (SEU) characterization of electronic components, requiring characteristics of radiation tolerance and employed in high-energy accelerators, relies on the **knowledge of high-energy hadron cross sections typically measured with high-energy protons**.

➔ **Pros:** exact cross section representative of the memory
Cons: facility availability, costs

- General **approach for SEUs induced by neutrons**: The memory is assumed to be equally sensitive to HEH above 20 MeV and a weighting function has to be accounted for the **intermediate energy neutrons**, considered from 0.2 MeV to 20 MeV, where the cross section is strongly energy dependent.

$$\Phi_{HEHeq} = \int_{0.2MeV}^{20MeV} w(E) \frac{d\phi_n(E)}{dE} dE + \int_{20MeV}^{+\infty} \frac{d\phi_{HEH}(E)}{dE} dE$$

Weibull function $w(E)$ convoluted with the differential flux.

- As the maximum energy of the Am-Be source is 10 MeV only the first term is considered and therefore the **Weibull function plays an important role**.

3. Americium-Beryllium source

- The Am-Be facility is located at CERN. Neutrons are generated by the beryllium after the absorption of an alpha particle emitted from the americium. The source **activity** is of **888 GBq**.

- The source is composed by a cylindrical capsule containing the two elements, which is housed below the floor. It can be easily turned on/off in a few seconds and once activated is maintained in the middle of the room inside the aluminium pipe by means of compressed air (see Fig. 1). This aspect allows an **isotropic flux of $5.03 \times 10^7 [s^{-1}/4\pi]$** .



Figure 1: CERN Am-Be facility irradiation room (to the left) and test position (to the right)

4. FLUKA simulations and measurements

- The **source provides a spectrum** with a peak around 3 MeV and reaches a **maximum energy of about 10 MeV** as shown in the FLUKA simulation of Fig. 2.

- The HEHeq flux (see section 2) of the Am-Be source is highly dependent on the Weibull function of the specific memory (Tab. 1).



It's therefore important to have an estimation of the Weibull fit of the new memory to test (for instance, with data on the same technology).

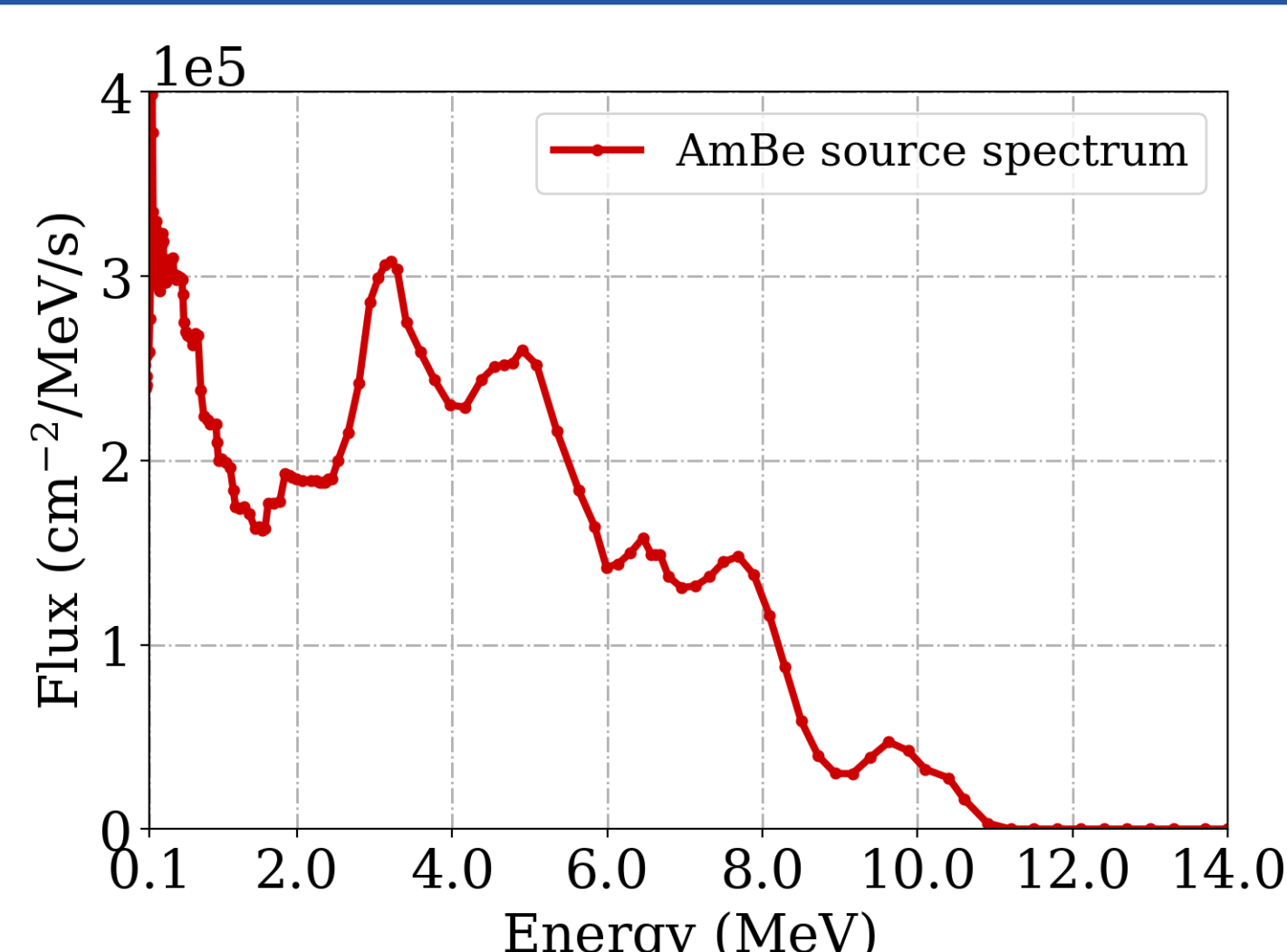


Figure 2: FLUKA Simulation of the Am-Be differential spectrum as a function of the energy (at the source edge). Axis are in linear scale to highlight the flux between 0.1 -10 MeV

5 cm	ESA M.	Cypress	Toshiba
HEHeq [cm ⁻² s ⁻¹]	9.3×10 ³	6.3×10 ³	1.8×10 ⁴

Table 1: FLUKA equivalent fluxes at 5 cm from the middle of the source. The considered response functions $w(E)$ were obtained using quasi-monoenergetic neutrons at PTB

Measurements

- The **ESA SEU Monitor** (0.25 μ m CMOS technology) is an SRAM-based detector calibrated in a broad set of facilities and used by the R2E project at CERN to **cross validate the facility flux**. In addition, it shows the beam **homogeneity** over its 20x20 mm² of active surface, very **well spread for the Am-be source** (see Fig. 3).
- The **source and irradiation room** were **modelled thought the Monte Carlo FLUKA tool** in order to estimate the flux of the source at the desired distance.
- Tests with the ESA Monitor were performed in different positions along the three axis with respect to the source, with the aim of evaluating in a qualitative way the flux attenuation (r^{-2} law) and compare these values with those from the simulations (see Fig. 4, 5).
- The ESA Monitor reference cross section for the flux measurements is considered the one in saturation at 230 MeV. The **measurements are in agreement with the simulations within the experimental uncertainty** (of 15%).

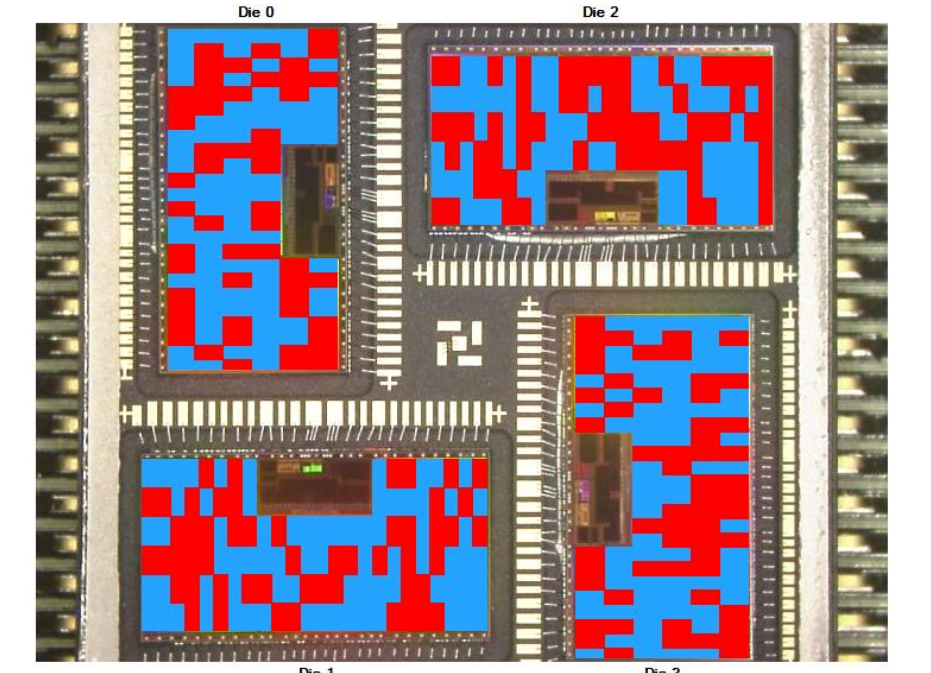


Figure 3: ESA Monitor homogeneity assessment at 5 cm from the source

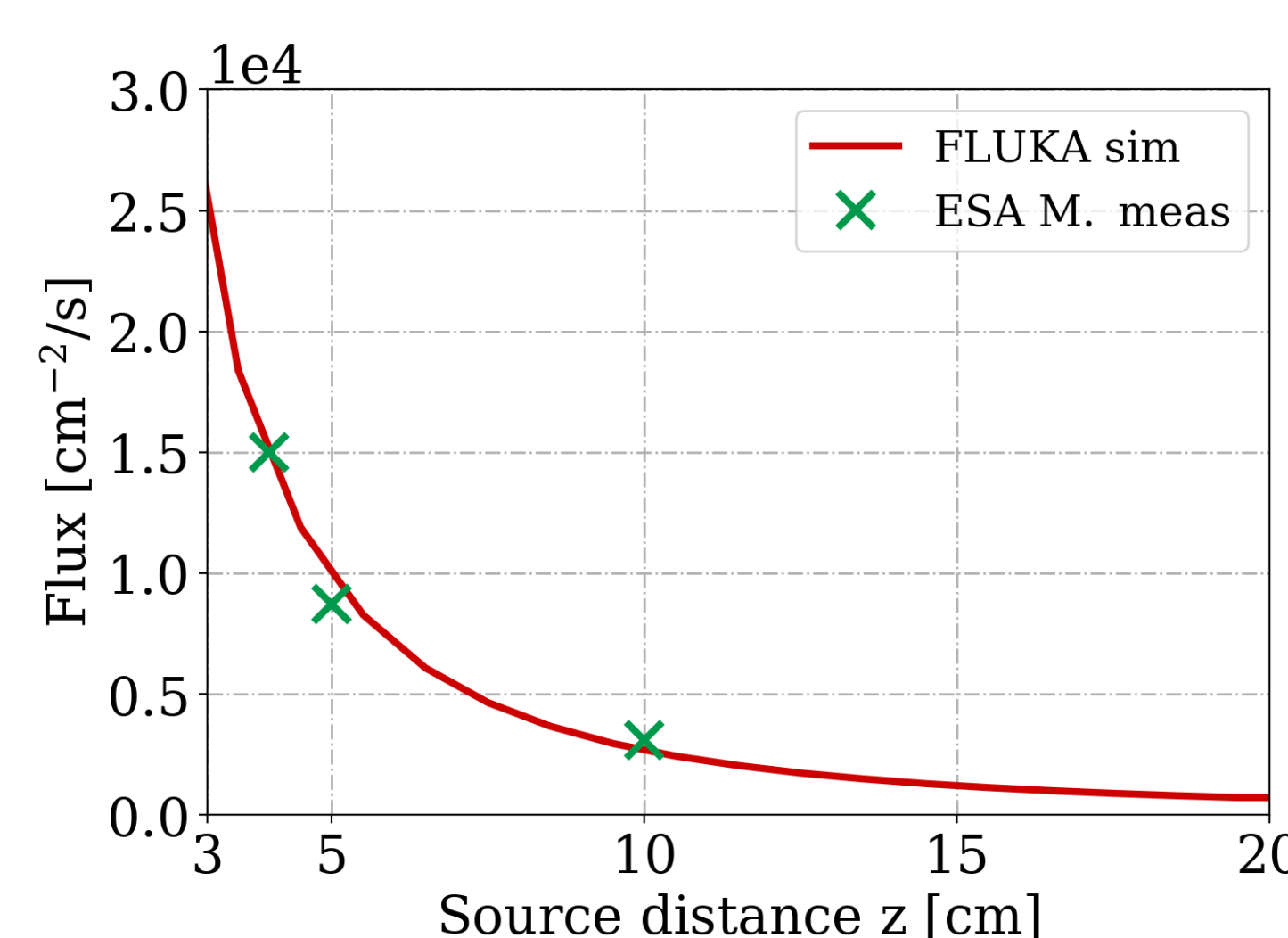


Figure 4: flux attenuation along the z (and x) axis, simulation and measurements

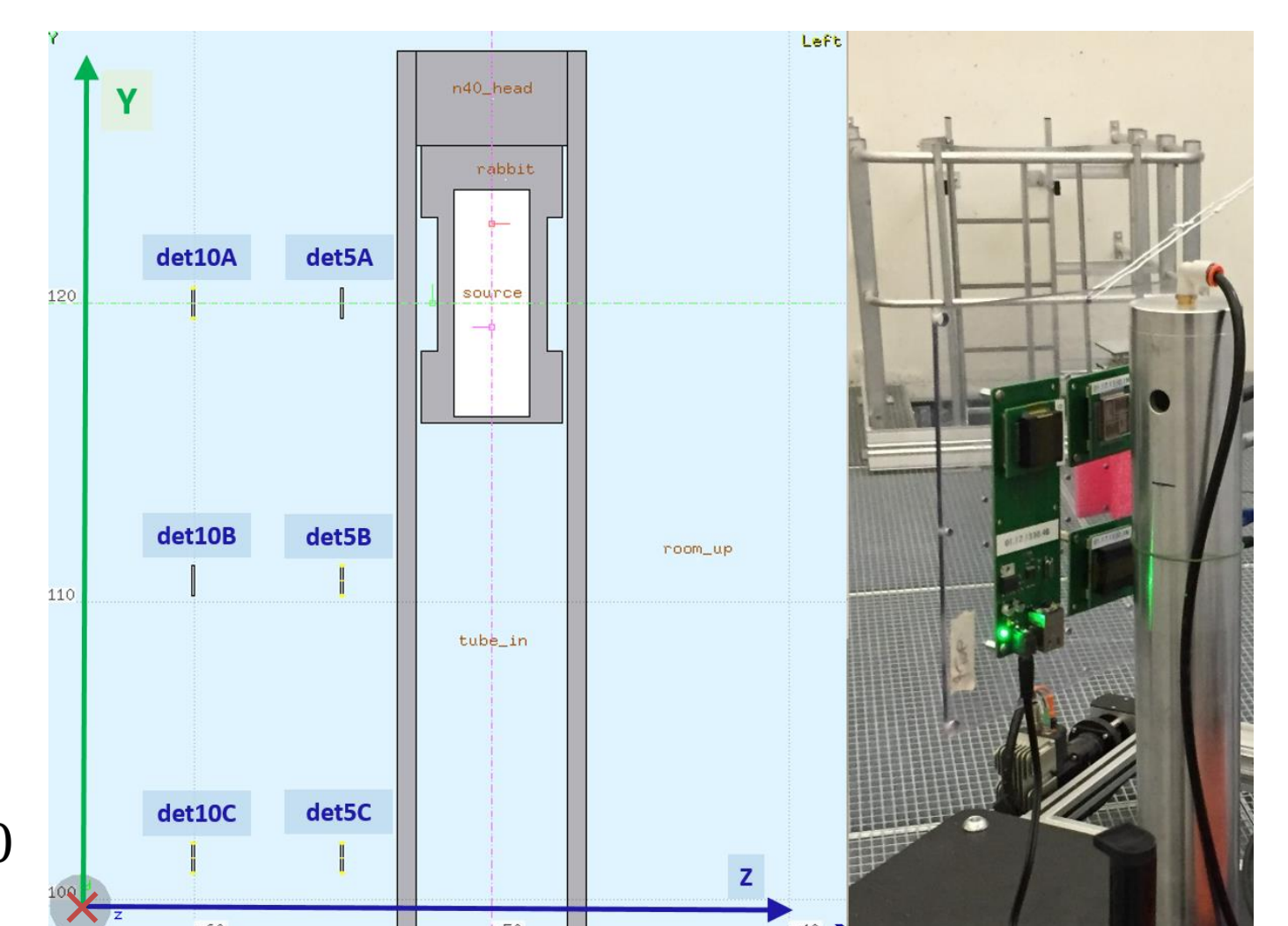


Figure 5: FLUKA source geometry with the different detector positions (to the left) and test with the ESA SEU Monitor (to the right)

5. Test results and comparison

- Together with the ESA Monitor, the **Cypress memory** (90 nm), embedded in the RadMon system used to measure the HEH flux along the LHC accelerator, was qualified.
- The **Am-Be SEU number** measured at 5 cm from the middle of the source are **compared** with the corresponding calculated values obtained by multiplying the HEHeq flux times the respective mono-energetic cross sections. The latter are considered at **230 MeV protons (PSI) for the ESA Monitor and 14 MeV neutrons (LPSC) for the Cypress**.
- The agreement for the ESA Monitor is impressive considering that the Am-Be source with energies <10 MeV yields an equivalent upset number as 230 MeV protons.



Pros: facility availability, costs, negligible activation after the irradiation
Cons: cross section is an estimation

5 cm from the source	ESA Monitor		Cypress	
	SEU/day	%	SEU/day	%
Experimental	332		799	
Calculated	355	-6.9	617	+23

Table 2: SEU results, the percentage refers to the upsets difference calculated considering the mono-energetic facility in comparison with those from the Am-Be source

6. Conclusions

- As shown, the **number of SEUs** retrieved by **using facilities with a wide range of energies**, from less than **10 MeV (Am-Be) up to 230 MeV (PSI)**, is **compatible** with each other. This is unfolded from the fact that the memory cross section follows the response curve implemented with the Weibull fit.
- The **Am-Be source** can therefore induce a statistically significant amount of **SEUs in a relatively reduced timeframe** (~hours), inducing a negligible activation level.
- Its employment can therefore be aimed at **screening the SEU sensitivity of SRAM memories** in a **more accessible and cost efficient way** compared to high-energy cyclotron proton testing.